

April 2009

# FDMA410NZ

# Single N-Channel 1.5 V Specified PowerTrench® MOSFET 20 V, 9.5 A, 23 m $\Omega$

#### **Features**

- Max  $r_{DS(on)}$  = 23 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 9.5 A
- Max  $r_{DS(on)}$  = 29 m $\Omega$  at  $V_{GS}$  = 2.5 V,  $I_D$  = 8.0 A
- Max  $r_{DS(on)}$  = 36 m $\Omega$  at  $V_{GS}$  = 1.8 V,  $I_D$  = 4.0 A
- Max  $r_{DS(on)}$  = 50 m $\Omega$  at  $V_{GS}$  = 1.5 V,  $I_D$  = 2.0 A
- HBM ESD protection level > 2.5 kV (Note 3)
- Low Profile-0.8 mm maximum in the new package MicroFET 2x2 mm
- Free from halogenated compounds and antimony oxides
- RoHS Compliant

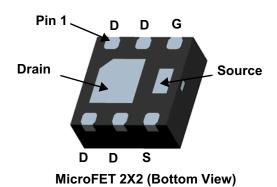


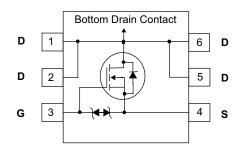
### **General Description**

This Single N-Channel MOSFET has been designed using Fairchild Semiconductor's advanced Power Trench process to optimize the  $r_{\text{DS}(\text{ON})}$  @  $V_{\text{GS}}$  = 1.5 V on special MicroFET leadframe.

#### **Applications**

- Li-Ion Battery Pack
- Baseband Switch
- Load Switch
- DC-DC Conversion





# MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Para	Ratings	Units			
V <sub>DS</sub>	Drain to Source Voltage			20	V	
$V_{GS}$	Gate to Source Voltage			±8	V	
	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	9.5		
ID	-Pulsed			24	A	
D	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.4	w	
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1b)	0.9		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempe	erature Range		-55 to +150	°C	

## **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	52	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	145	C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
410	FDMA410NZ	MicroFET 2X2	7 "	12 mm	3000 units

# Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		17		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 16 V, V <sub>GS</sub> = 0 V			1	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±8 V, V <sub>DS</sub> = 0 V			±10	μА

## **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	0.4	0.7	1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		-3		mV/°C
	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 9.5 A		17	23		
		$V_{GS} = 2.5 \text{ V}, I_D = 8.0 \text{ A}$		20	29	mΩ
	Static Drain to Source On Resistance	$V_{GS} = 1.8 \text{ V}, I_D = 4.0 \text{ A}$		24	36	
r <sub>DS(on)</sub>	Clair Brain to Course on Neoscario	$V_{GS} = 1.5 \text{ V}, I_D = 2.0 \text{ A}$		29	50	11152
		$V_{GS} = 4.5 \text{ V}, I_D = 9.5 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		23	32	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = 5 V, I <sub>D</sub> = 9.5 A		35		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V = 40 V V = 0 V	815	1080	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	130	175	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	85	130	pF
$R_a$	Gate Resistance	f = 1 MHz	2.1		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			7.5	15	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 9.5 A,		3.9	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		27	44	ns
t <sub>f</sub>	Fall Time			3.7	10	ns
$Q_g$	Total Gate Charge	V 45V V 40V		10	14	nC
Q <sub>gs</sub>	Gate to Source Charge	V <sub>GS</sub> = 4.5 V , V <sub>DD</sub> = 10 V,		1.2		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	ID - 3.3 A		2.0		nC

## **Drain-Source Diode Characteristics**

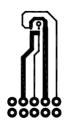
Is	Maximum Continuous Drain-Source Diode	Maximum Continuous Drain-Source Diode Forward Current			2.0	Α
$V_{SD}$	Source to Drain Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_S = 2.0 \text{ A}$ (Note 2)			0.7	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	- I <sub>E</sub> = 9.5 A, di/dt = 100 A/μs		12	22	ns
Q <sub>rr</sub>	Reverse Recovery Charge	- 1 <sub>F</sub> = 9.5 A, αι/αι = 100 A/μS		2.6	10	nC

#### NOTES:

<sup>1.</sup>  $R_{\theta JA}$  is determined with the device mounted on a 1 in 2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta JA}$  is determined by the user's board design.



a.52 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 145 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300  $\mu\text{s}$  , Duty cycle < 2.0%.

<sup>3.</sup> The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

# Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

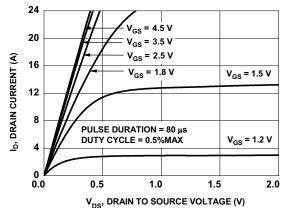


Figure 1. On-Region Characteristics

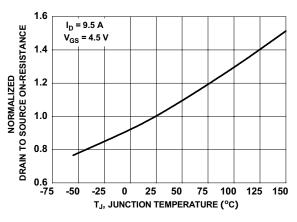


Figure 3. Normalized On-Resistance vs Junction Temperature

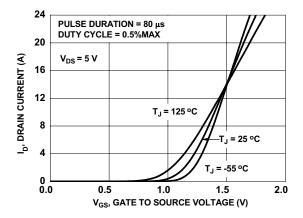


Figure 5. Transfer Characteristics

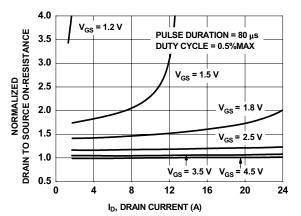


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

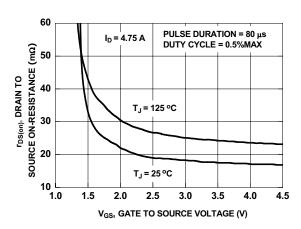


Figure 4. On-Resistance vs Gate to Source Voltage

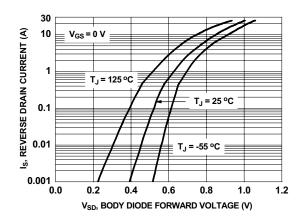


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

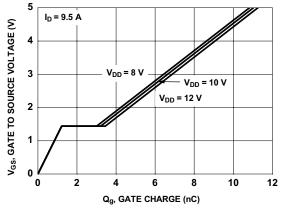


Figure 7. Gate Charge Characteristics

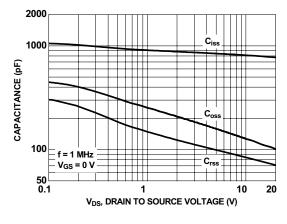


Figure 8. Capacitance vs Drain to Source Voltage

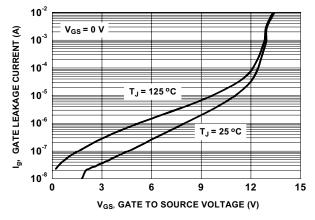


Figure 9. Gate Leakage Current vs Gate to Source Voltage

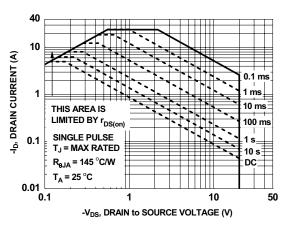


Figure 10. Forward Bias Safe Operation Area

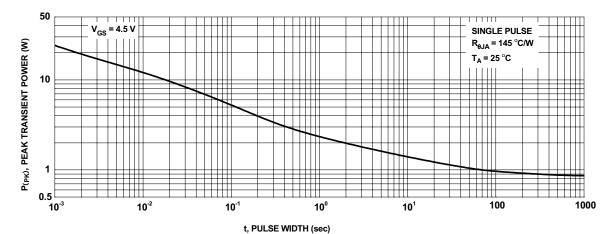


Figure 11. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

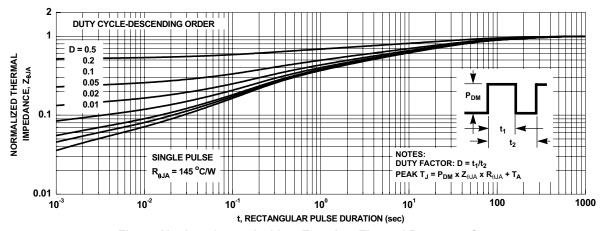
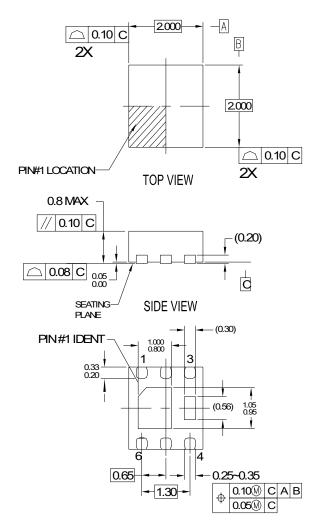
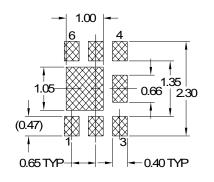


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

# **Dimensional Outline and Pad Layout**



RECOMMENDED LAND PATTERN OPT 1



RECOMMENDED LAND PATTERN OPT 2

**BOTTOM VIEW** 

#### NOTES:

- A DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-229 DATED AUG/2003
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. DRAWING FILENAME: MKT-MLP06Lrev2.





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